Unit: mm

TOSHIBA Transistor Silicon PNP Epitaxial Type

TPC6601

High-Speed Switching Applications DC-DC Converter Applications

- High DC current gain: $h_{FE} = 200 \text{ to } 500 \text{ (IC} = -0.3 \text{ A)}$
- Low collector-emitter saturation voltage: $V_{CE (sat)} = -0.2 \text{ V (max)}$
- High-speed switching: $t_f = 90 \text{ ns (typ.)}$

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Collector-base voltage		V _{CBO}	-50	V	
Collector-emitter voltage		V _{CEO}	-50	٧	
Emitter-base voltage		V _{EBO}	-7	٧	
Collector current	DC	IC	-2.0	А	
	Pulse	I _{CP}	-3.5		
Base current		IB	-0.2	Α	
Collector power dissipation	DC	PC	0.8	W	
	t = 10 s	(Note 1)	1.6		
Junction temperature		Tj	150	°C	
Storage temperature range		T _{stg}	-55 to 150	°C	

Note 1: Mounted on an FR4 board (glass epoxy, 1.6 mm thick, Cu area: 645 mm²)

1. Collector 2. Collector 3. Base 6. Collector 4. Emitter 5. Collector 6. Collector 7. Collector

Weight: 0.011 g (typ.)

Note 2: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current		I _{CBO}	$V_{CB} = -50 \text{ V}, I_E = 0$	_	_	-100	nA
Emitter cut-off current		I _{EBO}	$V_{EB} = -7 \text{ V}, I_{C} = 0$	_	_	-100	nA
Collector-emitter breakdown voltage		V (BR) CEO	$I_C = -10 \text{ mA}, I_B = 0$	-50			٧
DC current gain		h _{FE} (1)	$V_{CE} = -2 \text{ V}, I_{C} = -0.3 \text{ A}$	200	_	500	
		h _{FE} (2)	$V_{CE} = -2 \text{ V}, I_{C} = -1.0 \text{ A}$	100			
Collector-emitter saturation voltage		V _{CE (sat)}	$I_C = -1.0 \text{ A}, I_B = -33 \text{ mA}$	_	_	-0.2	V
Base-emitter saturation voltage		V _{BE (sat)}	$I_C = -1.0 \text{ A}, I_B = -33 \text{ mA}$	_	_	-1.1	V
Switching time	Rise time	t _r	See Figure 1 circuit diagram.	_	60	_	
	Storage time	t _{stg}	$V_{CC} \simeq -30 \text{ V}, R_L = 30 \Omega$	_	250	_	ns
	Fall time	t _f	$I_{B1} = -I_{B2} = -33 \text{ mA}$	_	90	_	

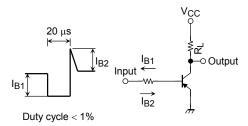
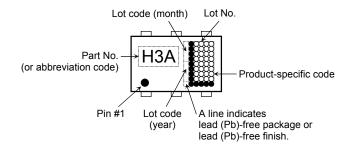


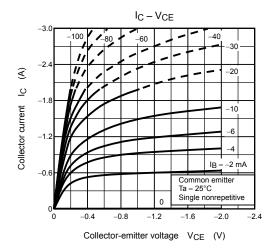
Figure 1 Switching Time Test Circuit & Timing Chart

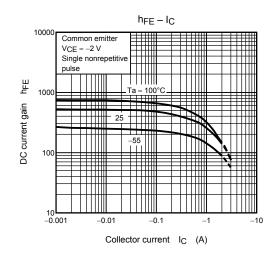
Circuit Configuration

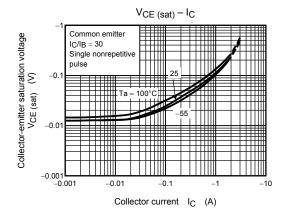
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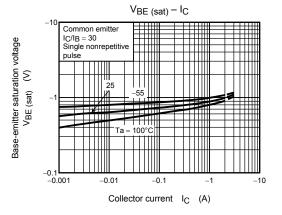
Marking

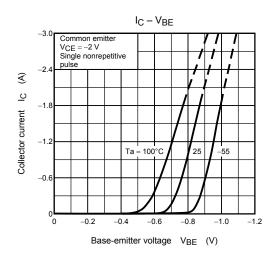




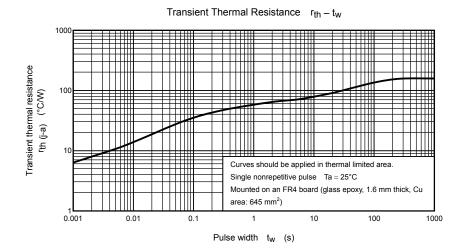


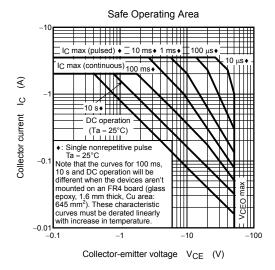






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